Se	earch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	•
09/965,784	MCELWAIN ET AL.	
Examiner	Art Unit	
Tuan H. Nauven	2618	

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Class	Subclass	Date	Examiner
455	412.1,415, 426.1	12/15/2006	T.N
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
All searches are on EAST data base.	12/15/2006	T.N
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